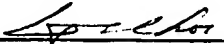


Sheet 1 of 1 SECOND IDS LIST OF REFERENCES CITED BY APPLICANT (FORM PTO-1449) DATED: May 17, 2006		Atty. Docket No.: 4633		Serial No.: 10/791,627	
		Applicant: Keiichi KURAMOTO et al.			
		U.S. Filing Date: March 1, 2004		Art Unit: 1713	
U. S. PATENT DOCUMENTS					
EXAMINER IN 2/11/06	DOCUMENT NO.	DATE	NAME	Cl.	Sub-Cl.
FOREIGN PATENT DOCUMENTS					
		DOCUMENT NO.	DATE	COUNTRY	Cl.
	AG	9-311234	12/1997	Japan	-
	AH	10-101717	04/1998	Japan	-
OTHER DOCUMENTS					
EXAMINER'S SIGNATURE 			DATE CONSIDERED 9/12/06		
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

Sheet 1 of 1
**THIRD IDS LIST OF REFERENCES
 CITED BY APPLICANT**
 (FORM PTO-1449)
 DATE: July 7, 2006

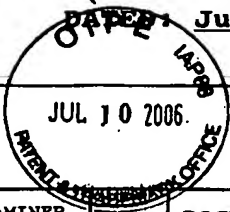
Atty. Docket No.:
 4633

Serial No.:
 10/791,627

Applicant: Keiichi KURAMOTO et al.

U.S. Filing Date: 03/01/04

Art Unit:
 1713



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*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	Cl.	Sub- Cl.	Fil. Date
<i>AI</i>	AI	6,632,585	10/2003	Nakamura	-	-	-

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		DOCUMENT NO.	DATE	COUNTRY	Cl.	Sub- Cl.	English
<i>AJ</i>	AJ	WO 01/037049	05/2001	PCT	-	-	=AI, Abst

OTHER DOCUMENTS

<i>AK</i>	AK	English Translation of JP 09-311234 published 12/1997.					
<i>AL</i>	AL	English Translation of JP 10-101717 published 04/1998.					

EXAMINER'S SIGNATURE

DATE CONSIDERED

Loelcher

9/12/06

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